Artificial Intelligence (AI) for Image Processing

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Message from the Guest Editor

Dear Colleagues,

The main aim of this Special Issue is to capture recent contributions of high-quality papers focusing on advanced image processing and analysis applications, including medical images, remote sensing images, galaxy images, and others. We are pleased to invite our colleagues to contribute original research papers as well as review papers that focus on the applications of artificial intelligence methods, including traditional machine learning methods, advanced deep learning approaches, metaheuristic optimization algorithms, and other AI-based methods for solving image processing problems.

The topics of this Special Issue include (but are not limited to) the following:

- Image classification and recognition
- Machine learning for image processing
- Metaheuristic optimization algorithms for image processing
- Remote sensing image classification
- Medical image classification
- Neural computing for image processing
- Evolutionary algorithms for image processing

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Guest Editor

Special Issue

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Message from the Editor-in-Chief

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